Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((measuring adj unit) with first adj connector with substrate near4 socket same second adj connector). clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 20:39
S1	35729	test\$4 near5 (IC! or integrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 20:38
S2	47	BOST and S1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:00
S 3	5	(("3,733,587") or ("3,764,995")).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/10 10:00
S4	9002	324/765,763,760,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:29
S5	35729	test\$4 near5 (IC! or integrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:30
S6	2798	S4 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:30
S7	11	S6 and ancillary	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:31
S8	347	S6 and measur\$4 and analyz\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:28

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S9	1135	714/736,734.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:33
S10	487	S9 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:33
S11	68	S10 and measur\$4 and analyz\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:35
S12	200	702/118.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:34
S13	83	S12 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:34
S14	18	S13 and measur\$4 and analyz\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/10 10:34
S15	11941	324/755-765,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/15 20:01
S16	5	"5931962"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 15:14
S17	5	(("3733587") or ("3764995")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/30 11:12
S18	9	("3733587").URPN.	USPAT	OR	ON	2005/03/30 14:14
S19	1	"3585599".PN.	USPAT; USOCR	OR	ON	2005/03/30 11:24

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S20	2	"3518413".PN.	USPAT; USOCR	OR	ON	2005/03/30 11:24
S21	4055	control\$4 adj card	USPAT	OR	ON	2005/03/30 14:15
S22	37240	test\$4 near5 (IC! or integrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/30 14:15
S23	73	S22 and S21	USPAT	OR	ON	2005/03/30 15:22
S24	4	S23 and 324/765,763,158.1.ccls.	USPAT	OR	ON	2005/03/30 15:41
S25	0	pluralilty near3 measur\$4 adj unit	USPAT	OR	ON	2005/03/30 15:23
S26	1	pluralilty near3 measur\$4	USPAT	OR	ON .	2005/03/30 15:24
S27	123	plurality near3 measur\$4 adj unit	USPAT	OR	ON	2005/03/30 15:24
S28	0	S27 and S24	USPAT	OR	ON	2005/03/30 15:24
S29	5	S27 and 324/765,763,158.1.ccls.	USPAT	OR	ON	2005/03/30 15:40
S30	11	measur\$4 adj unit near5 socket	USPAT	OR	ON	2005/03/30 15:41
S31	2	S30 and 324/765,763,158.1.ccls.	USPAT	OR	ON	2005/03/30 15:42
S32	2189	324/765.ccls.	USPAT	OR	ON	2005/03/30 15:42
S33	448	S32 and socket	USPAT	OR	ON	2005/03/30 15:42
S34	35	S32 and socket with measur\$4	USPAT	OR	ON	2005/03/30 15:43
S35	2	("5931962").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/30 19:23
S36	49	manufacturing adj2 (contact adj probe)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/30 19:24
S37	10981	324/760-765,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 16:19
S38	38966	test\$4 near5 (IC! or integrated adj circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 16:19
S39	3505	S38 and S37	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 16:19

S40	36	(measur\$4 and analyz\$4 and test\$4) with (computer or control\$4) and diagnostic adj signal	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 16:22
S41	1	S39 and S40	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 16:21
S42	5273	324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:26
S43	62692	test\$4 near5 (integrated adj circuit or IC or chip)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:28
S44	1665	S42 and S43	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:28
S45	31949	measur\$4 and analyz\$4 with computer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:28
S46	28	S44 and S45	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:39
S47	4524	324/765.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:39
S48	2172	S43 and S47	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:39
S49	22	S45 and S48	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:42

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S50	787	324/763.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:42
S51	540	S43 and S50	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:42
S52	12	S45 and S51	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 16:44
S53	6	(("3733587") or ("3764995")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/01 16:44
S54	89886	(test\$4 or measur\$4 or analyz\$4) near5 (ic or integrated adj circuit or chip)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:00
S55	10440	324/763,760,765,158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:01
S56	4436	S54 and S55	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:01
S57	1548	connect\$4 near5 substrate with socket	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:02
S58	48	S56 and S57	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:35
S59	1230	714/734,736.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:36

S60	0	S57 and S59	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:36
S61	623	S54 and S59	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:36
S62	133304	connect\$4 with socket	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:36
S63	24	S61 and S62	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:39
S64	295	702/118.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:39
S65	11	S62 and S64	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:41
S66	98	(measur\$4 or test\$4) with (first adj connector) and (second adj connector) and socket	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:42
S67	20	S55 and S66	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:46
S68	0	S66 and S59	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:46
S69	0	S66 and S64	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 20:46